

The $e^- + e^+$ flux measurement with the AMS experiment on ISS

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On behalf of the AMS Collaboration



The (e^+e^-) flux measurement



$$\Phi(E, E + \Delta E) = \frac{N_{obs}(E, E + \Delta E)}{\Delta E \Delta T_{exp} A_{eff} \epsilon_{trig}}$$

F = Absolute differential flux ($m^{-2} sr^{-1} GeV^{-1}$)

N_{obs} = Number of observed events

DT_{exp} = Exposure time (s)

A_{eff} = effective acceptance (m^2sr)

ϵ_{trig} = trigger efficiency

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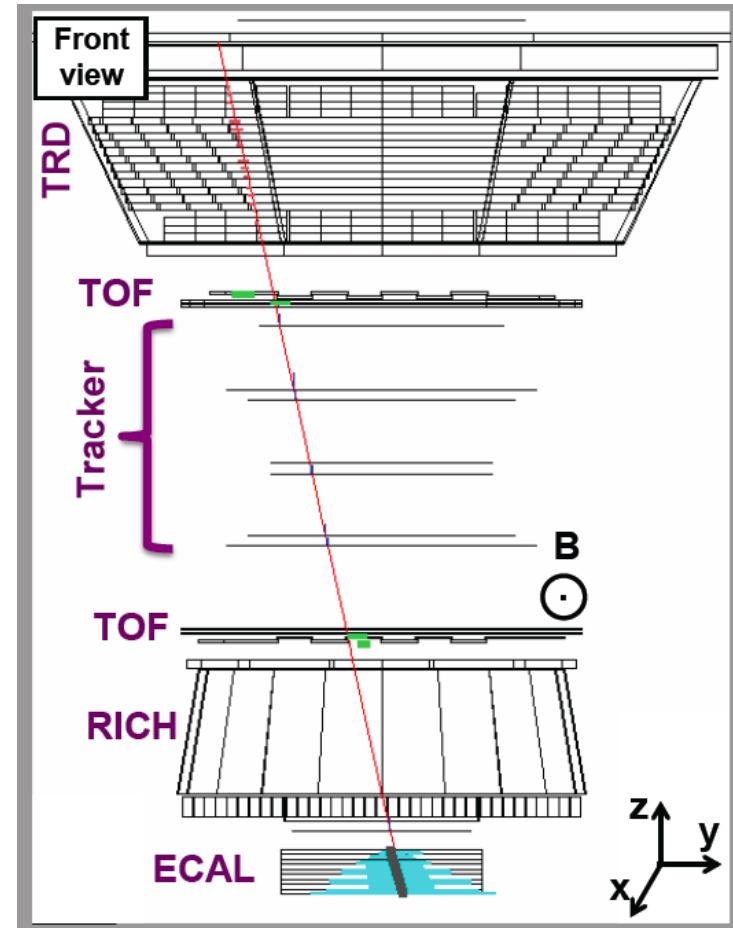
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Event selection

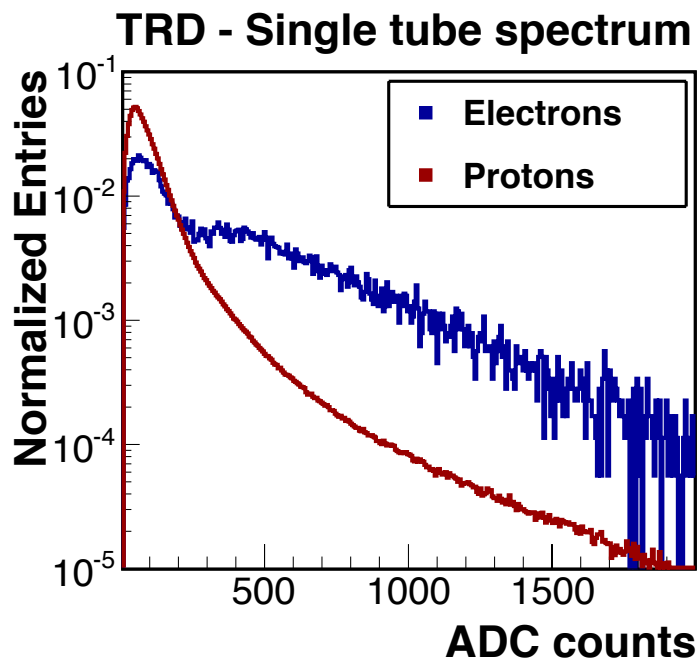


- **DAQ:** efficient data periods (no SAA)
- **Geomagnetic effects:** $E > 1.25$ max cutoff
- **TRD :**
- Minimum 8 hits used for e/p identification
- **TOF :** relativistic down-going particle
- **ECAL:**
 - Shower axis within the fiducial volume
 - Electromagnetic shape of the shower (BDT estimator)
- **TRACKER**
 - $Z < 1.5$ from tracker
 - track/ECAL matching to define fiducial volume

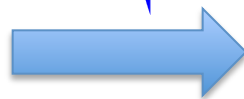
600 GeV electron



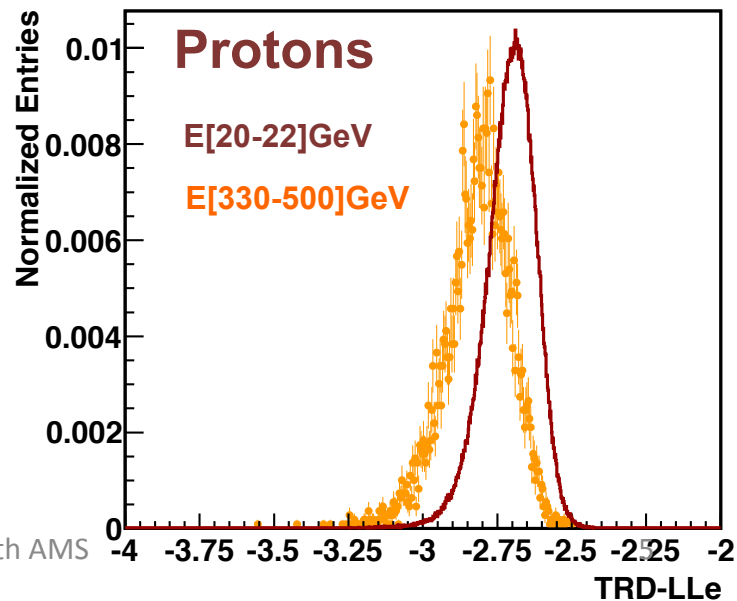
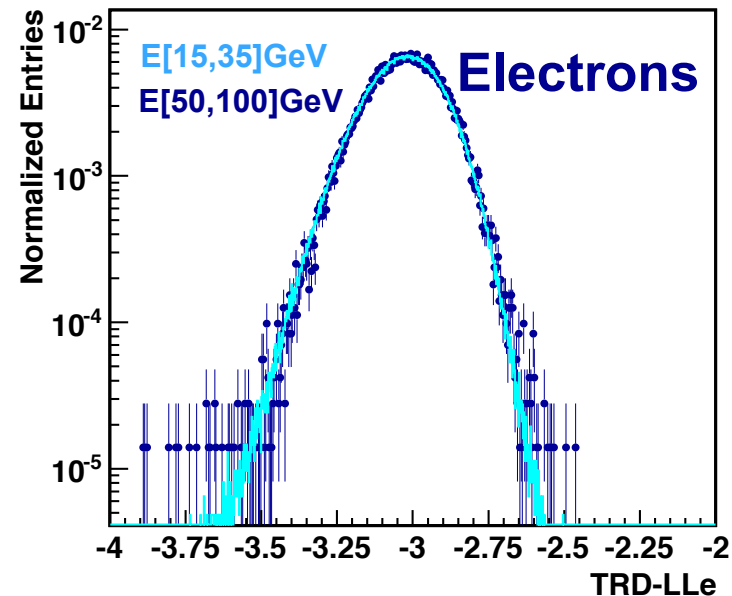
TRD e/p templates



$$P_e = \sqrt[n]{\prod_i^n P_e^{(i)}(A)}$$



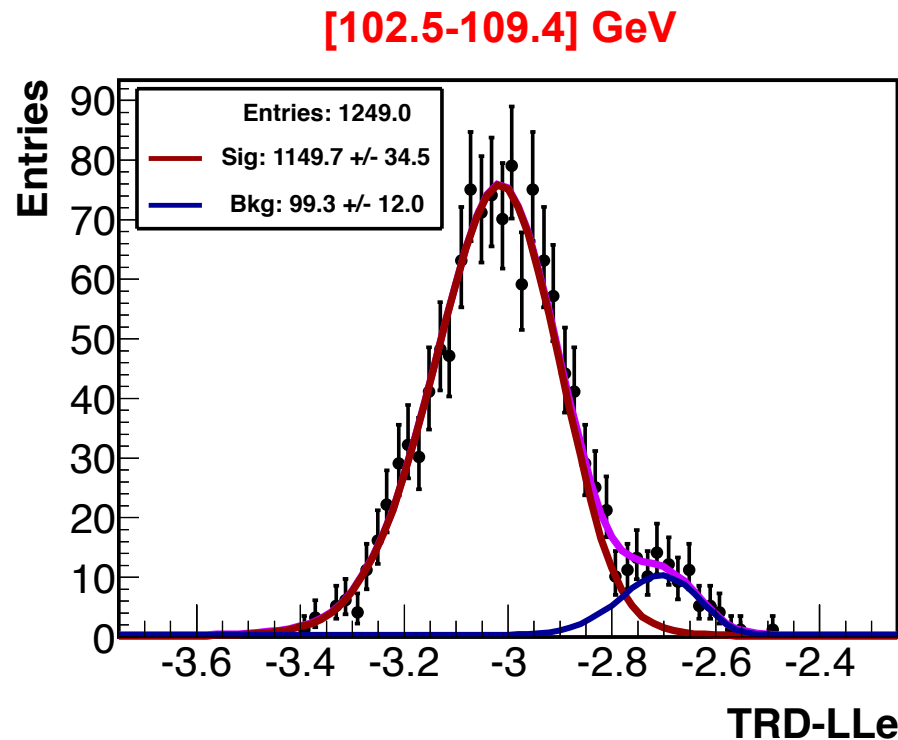
$$\text{TRD-LLe} = \text{Log}_{10}(P_e)$$



Analysis : 1D fit to measure N_e and N_p



Reference spectra for the signal and the background are fitted to data as a function of the TRD estimator for different cuts on the ECAL BDT estimator



Measurement is performed for the BDT cut that minimizes the overall statistical +systematic uncertainty

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Exposure Time

- ✓ Data taking period: 19 May 2011 - 19 May 2013
- ✓ Total exposure time used above 25 GeV: 51.2×10^6 s
- ✓ Average life time fraction $T_{\text{exp}}/2$ years = 81.6 %

The (e^+e^-) flux measurement

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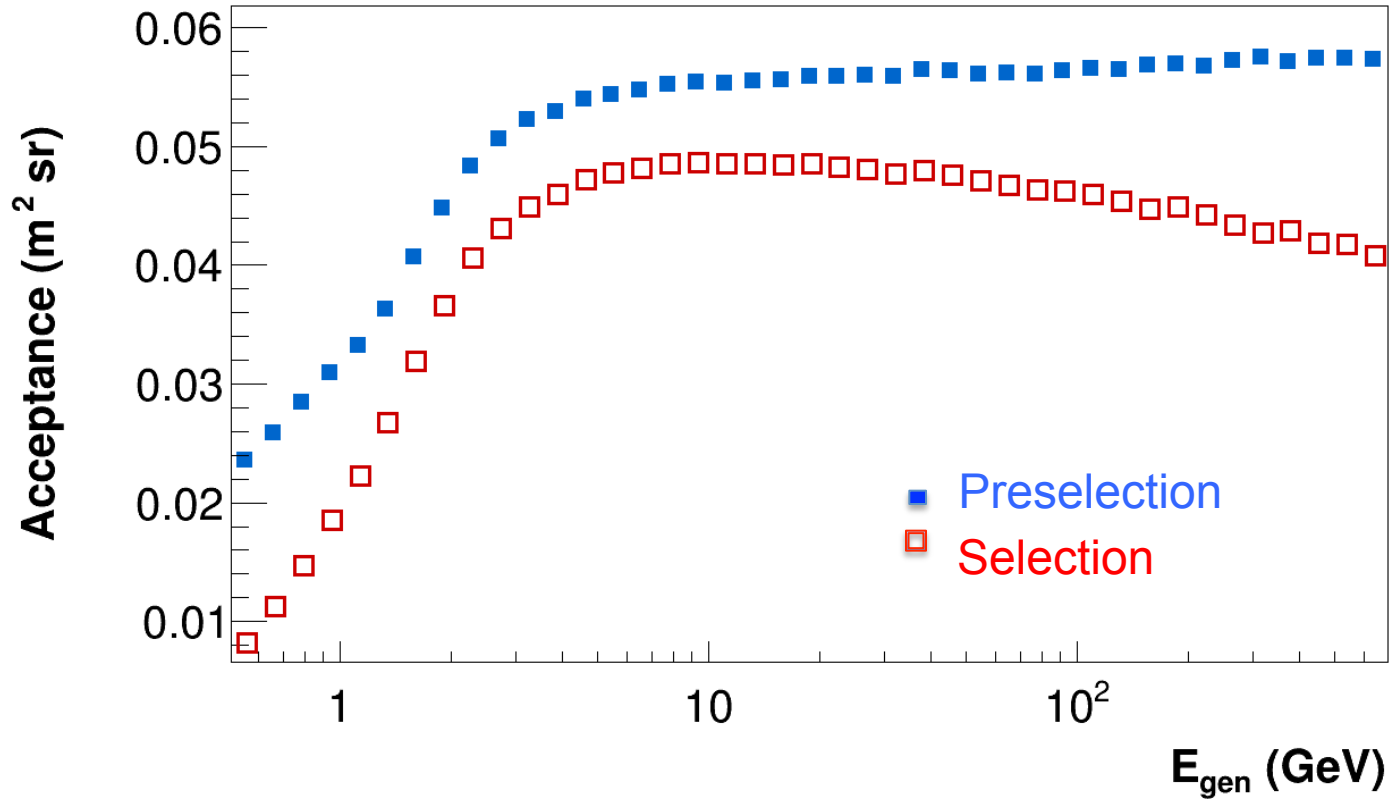
Acceptance

- Estimated with MC (Geant 4)

$$A_{\text{eff.}}(E) = A_{\text{generated}} \times \frac{N_{\text{selected}}(E)}{N_{\text{generated}}(E)}$$

- $A_{\text{generated}}$ = acceptance of the generation surface
- N_{selected} = events passing the selection criteria

Acceptance



The (e^+e^-) flux measurement

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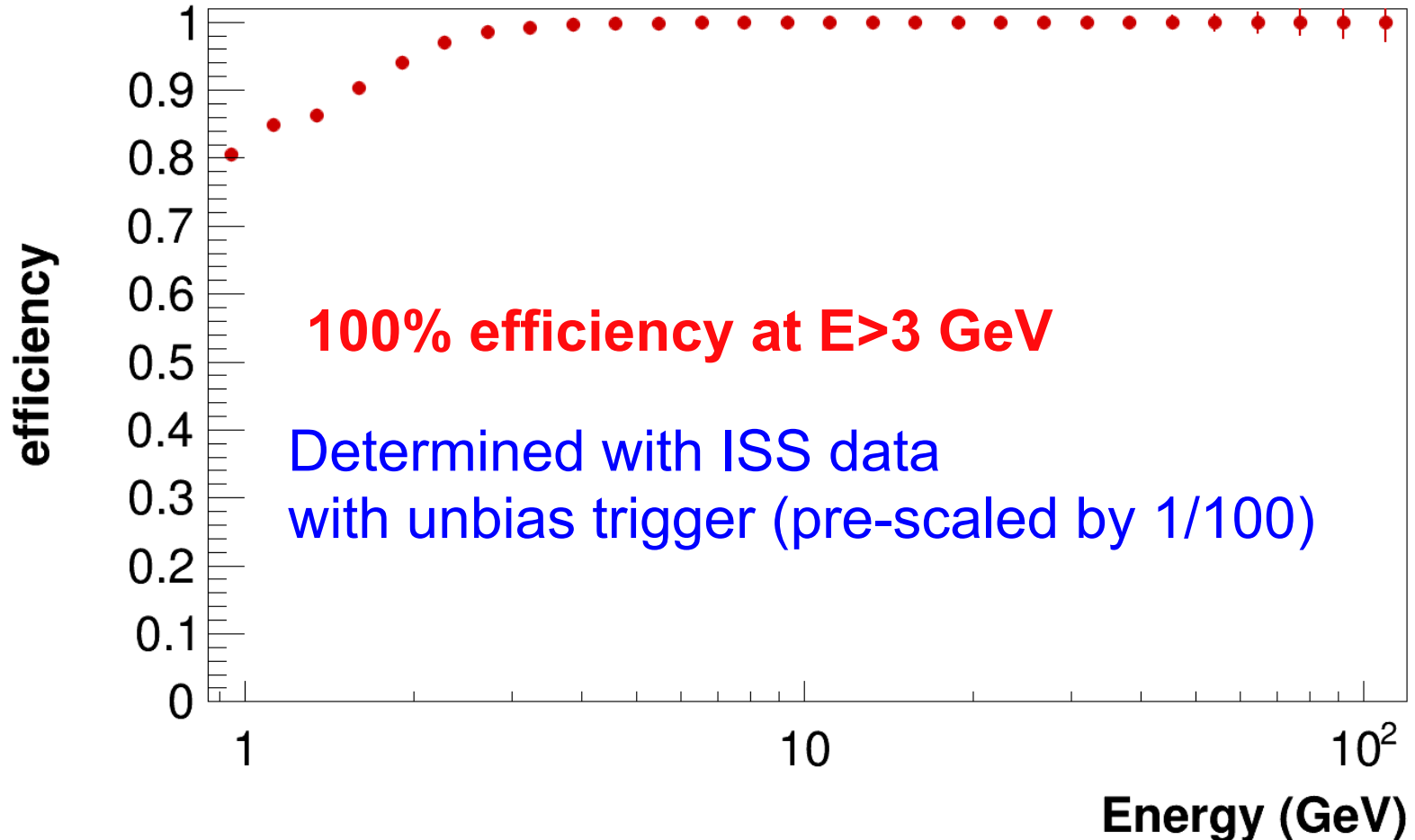
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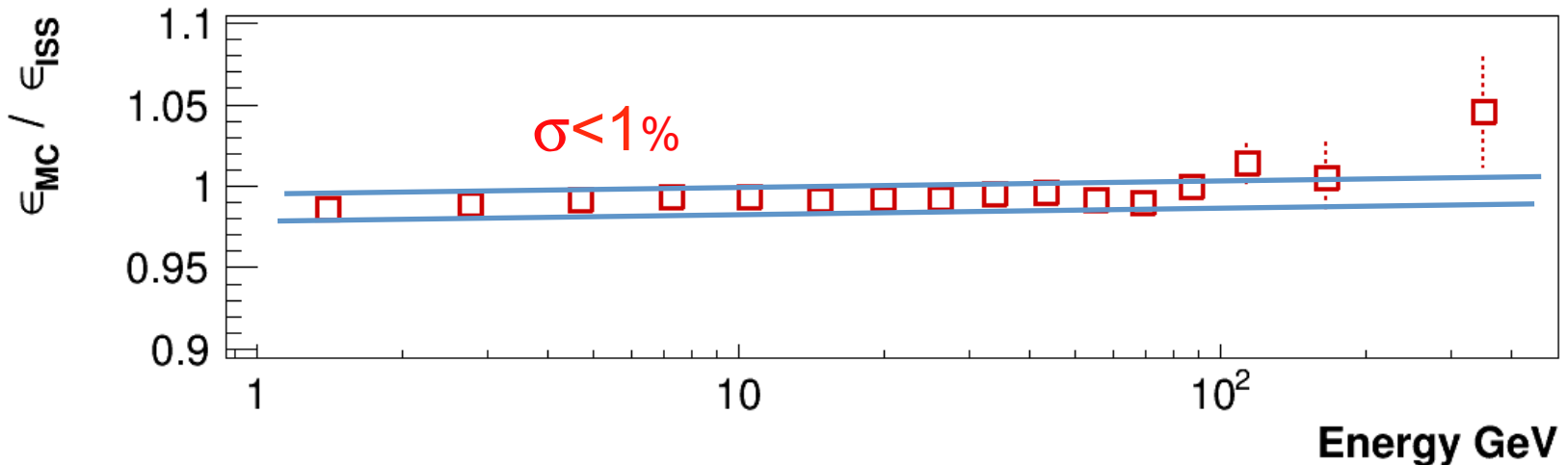
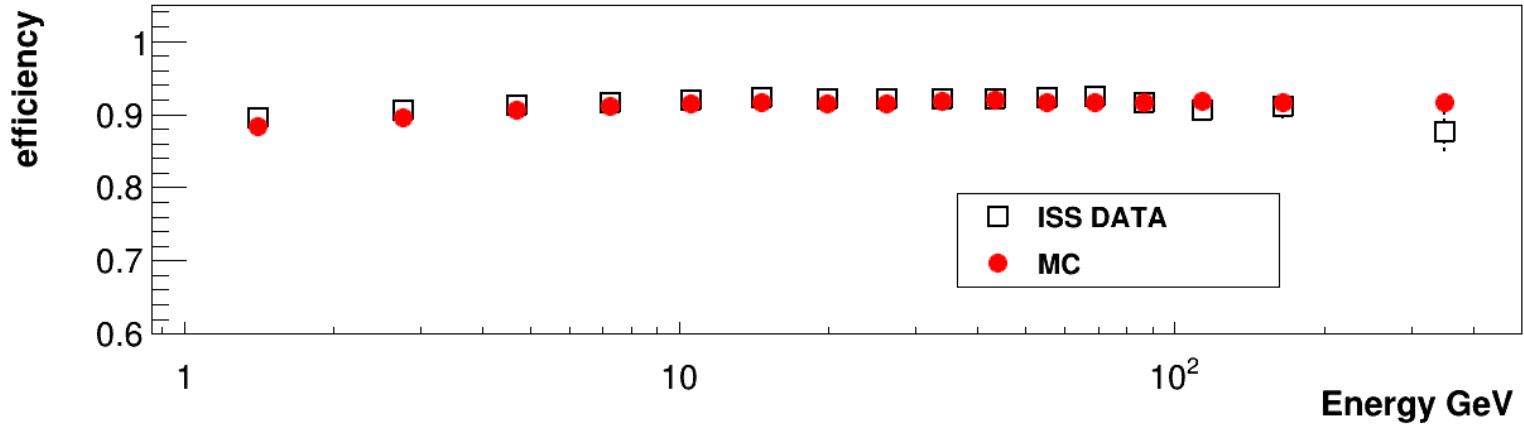
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The trigger efficiency



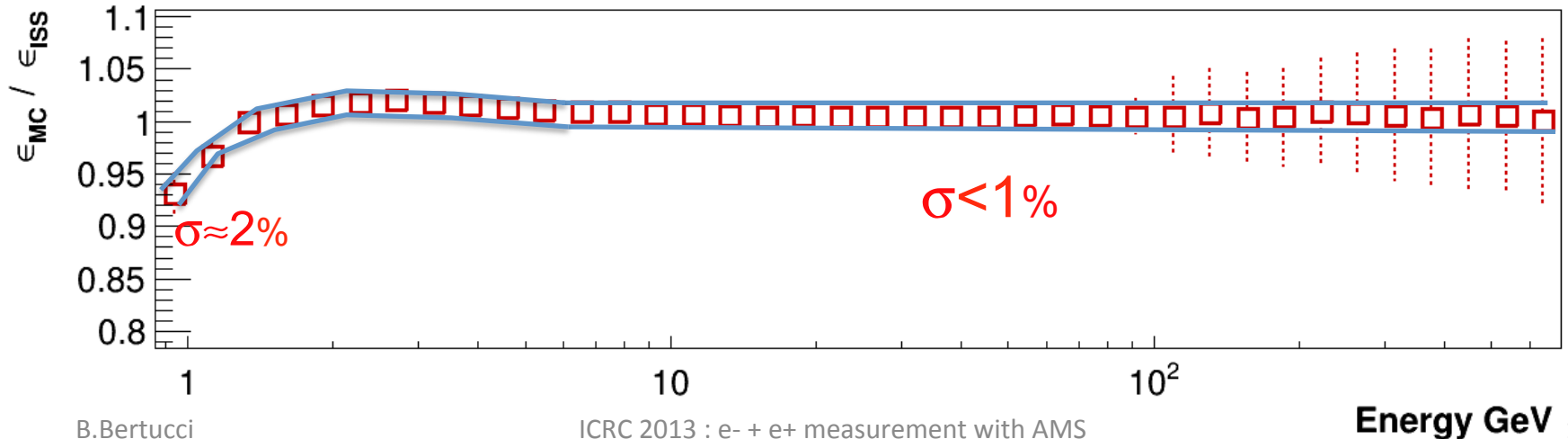
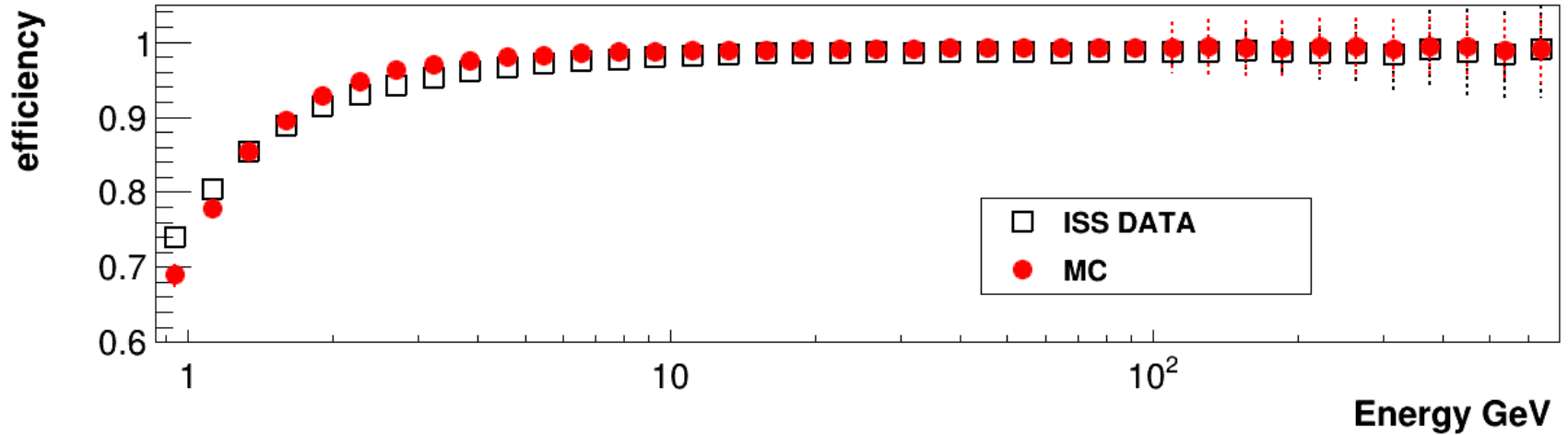
Systematic error

Track reconstruction: $\frac{\text{\# of electrons with a track}}{\text{\# of electrons passing through TRK acceptance}}$



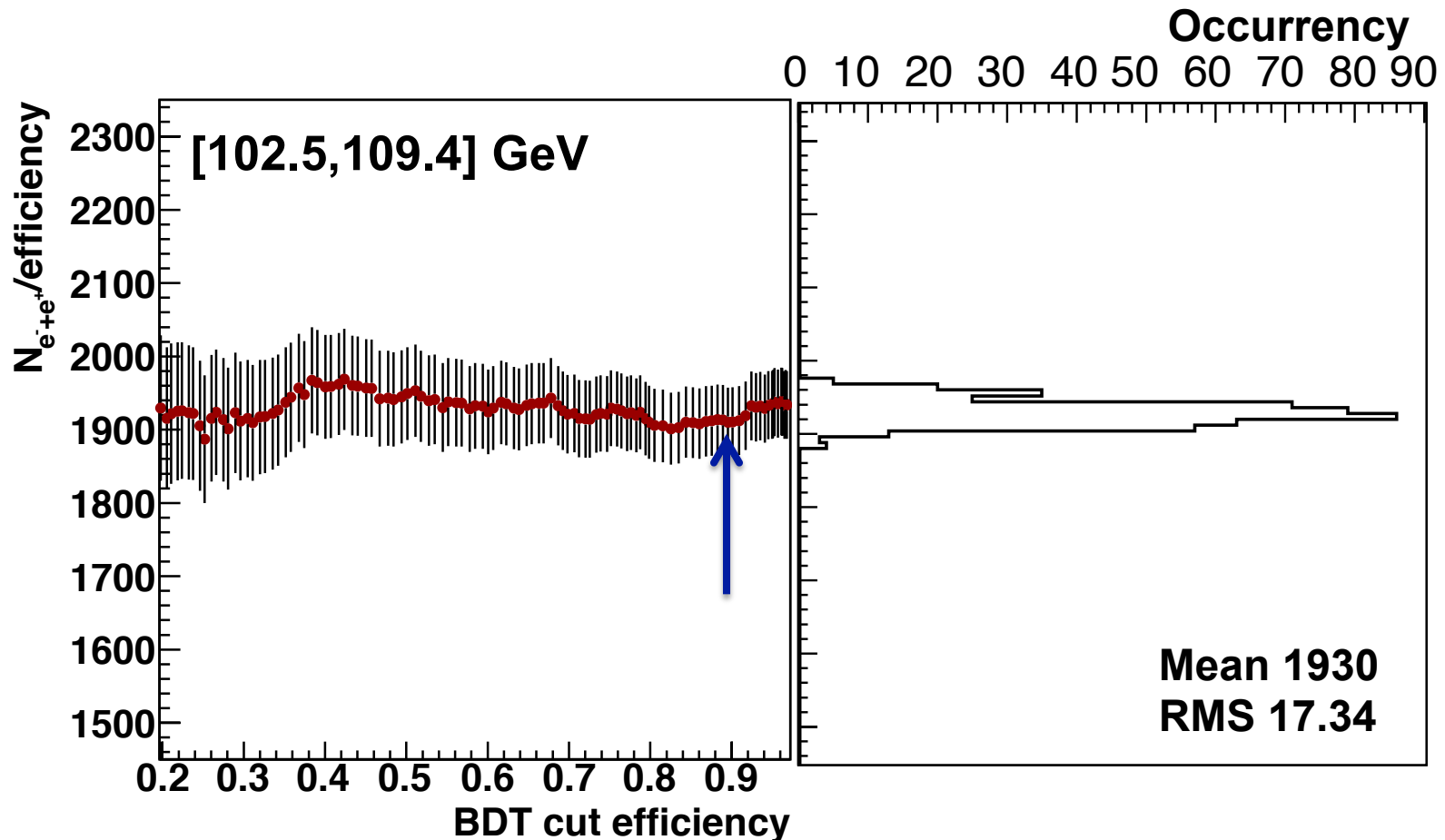
Systematic error

≥ 8 TRD hits used in the estimator

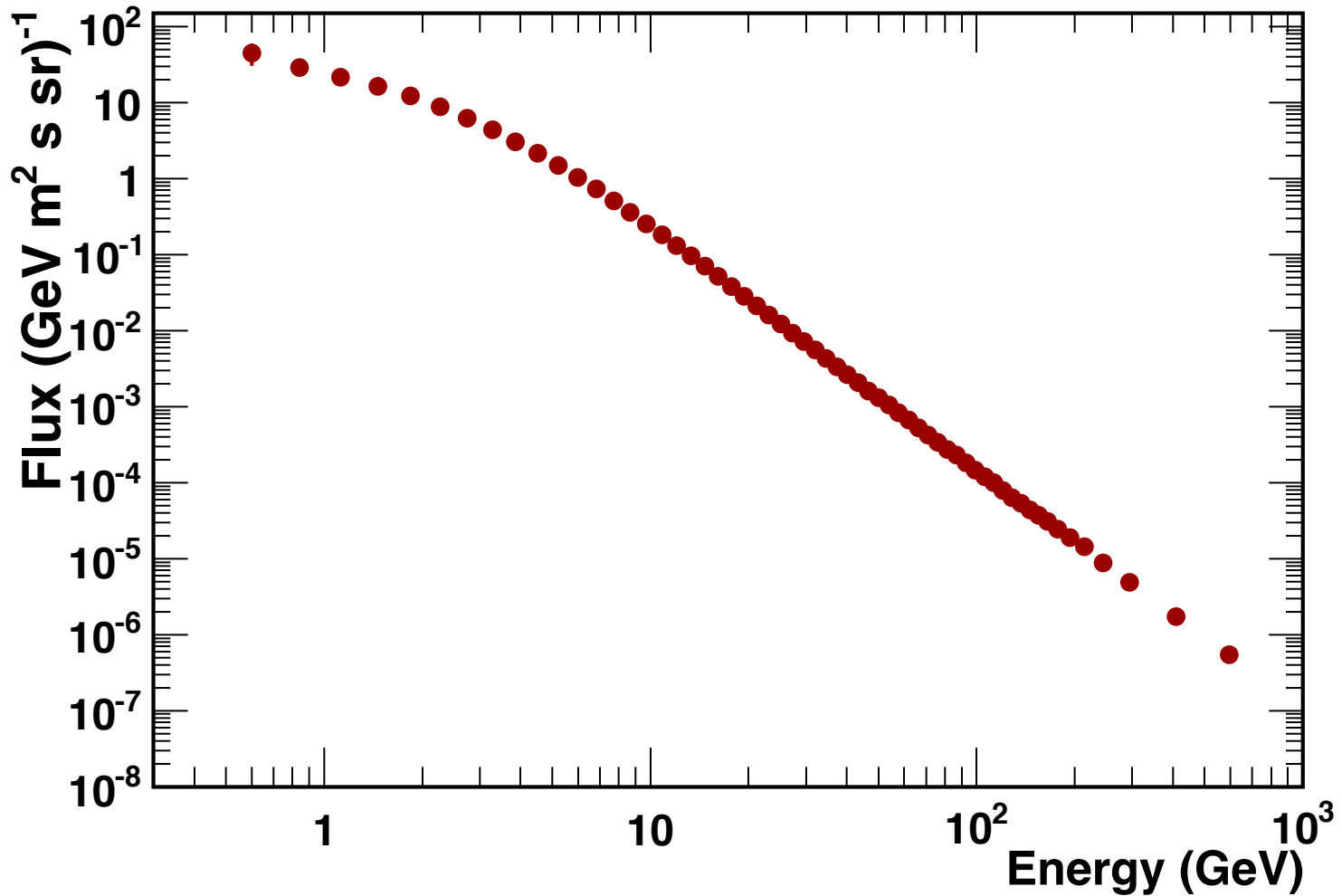


Systematic error: stability of the signal vs ECAL BDT cut

In each energy interval the cut on the ECAL BDT has been varied around the working point to verify the stability of the measurement.

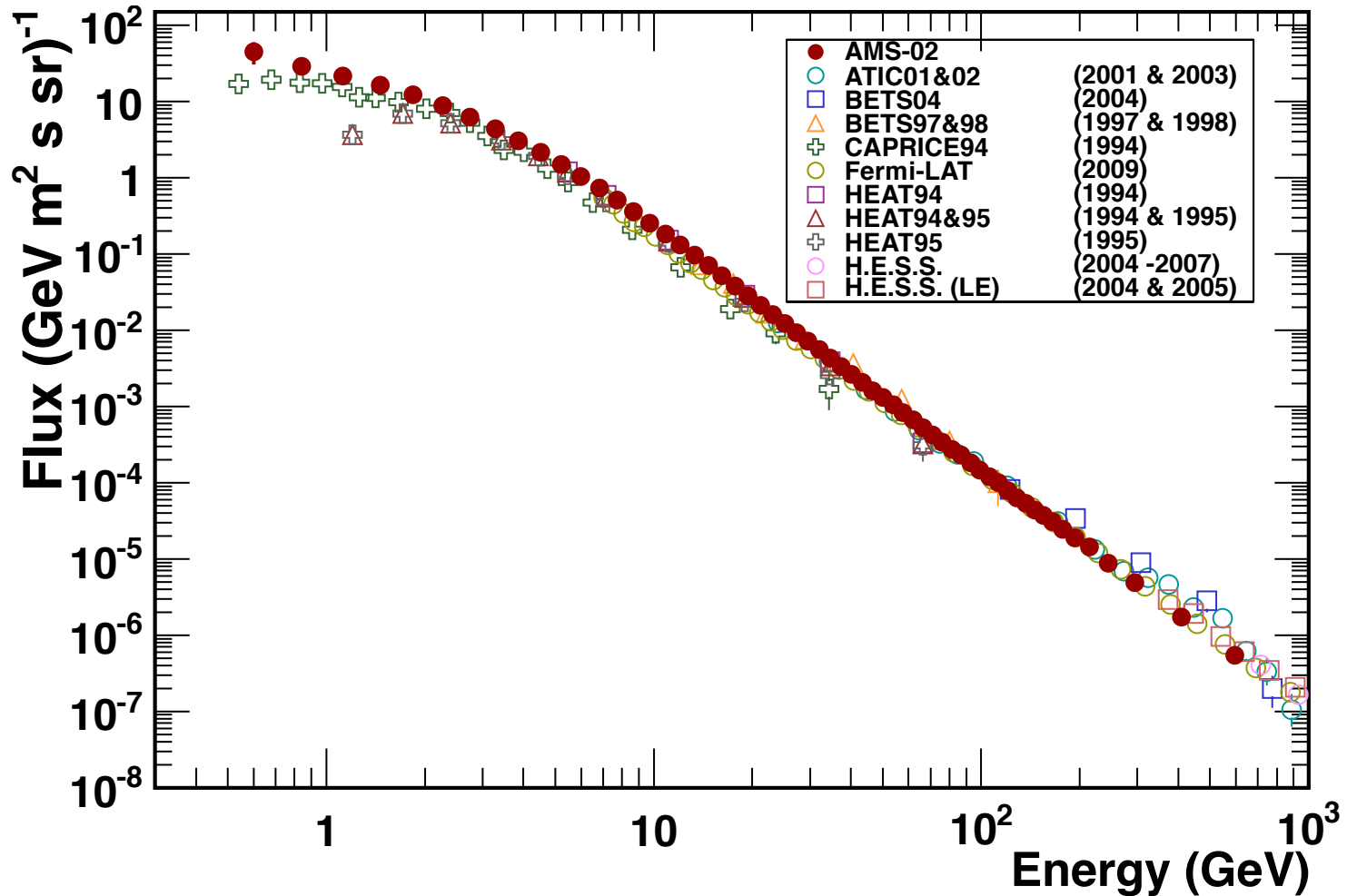


The ($e^- + e^+$) flux

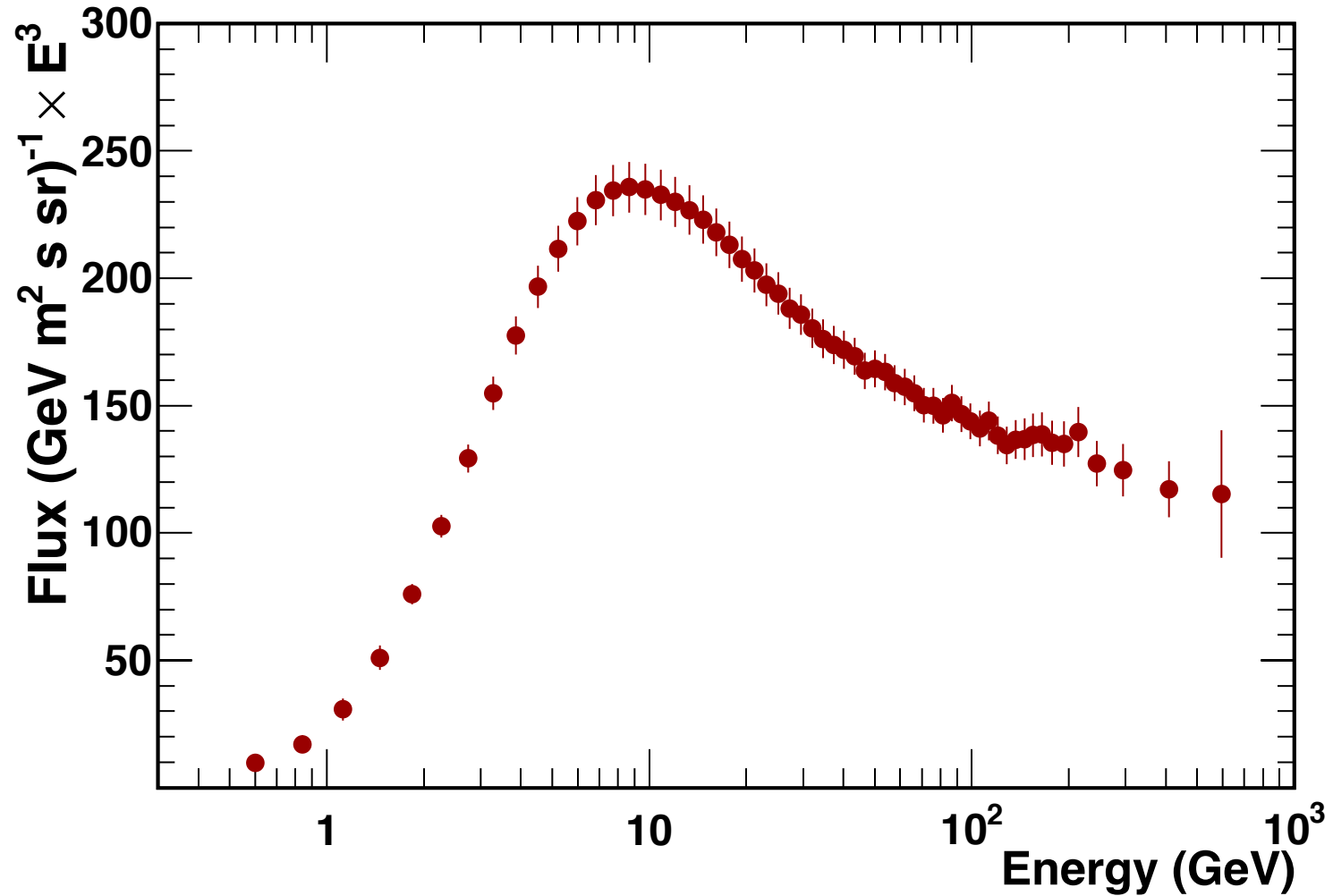




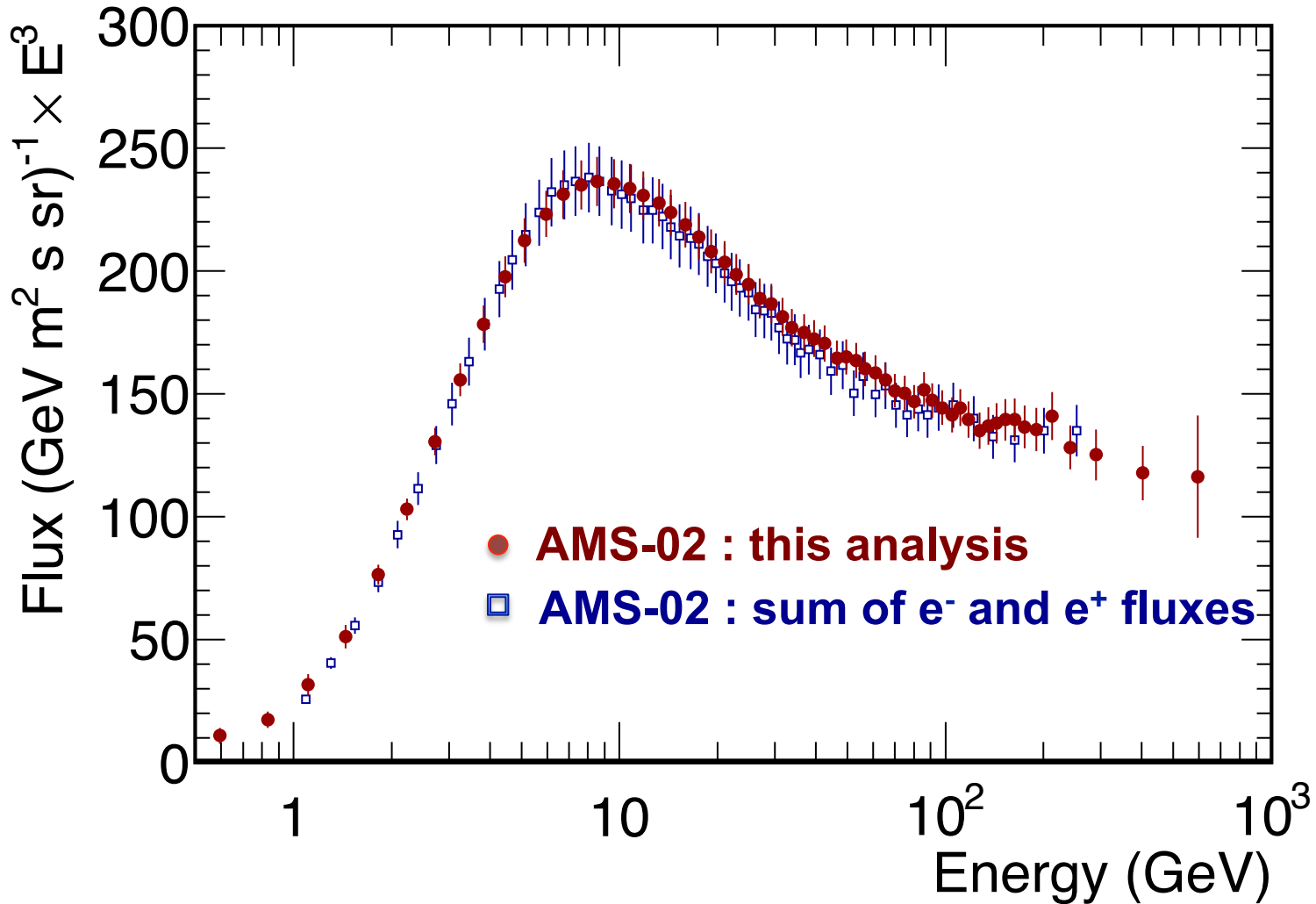
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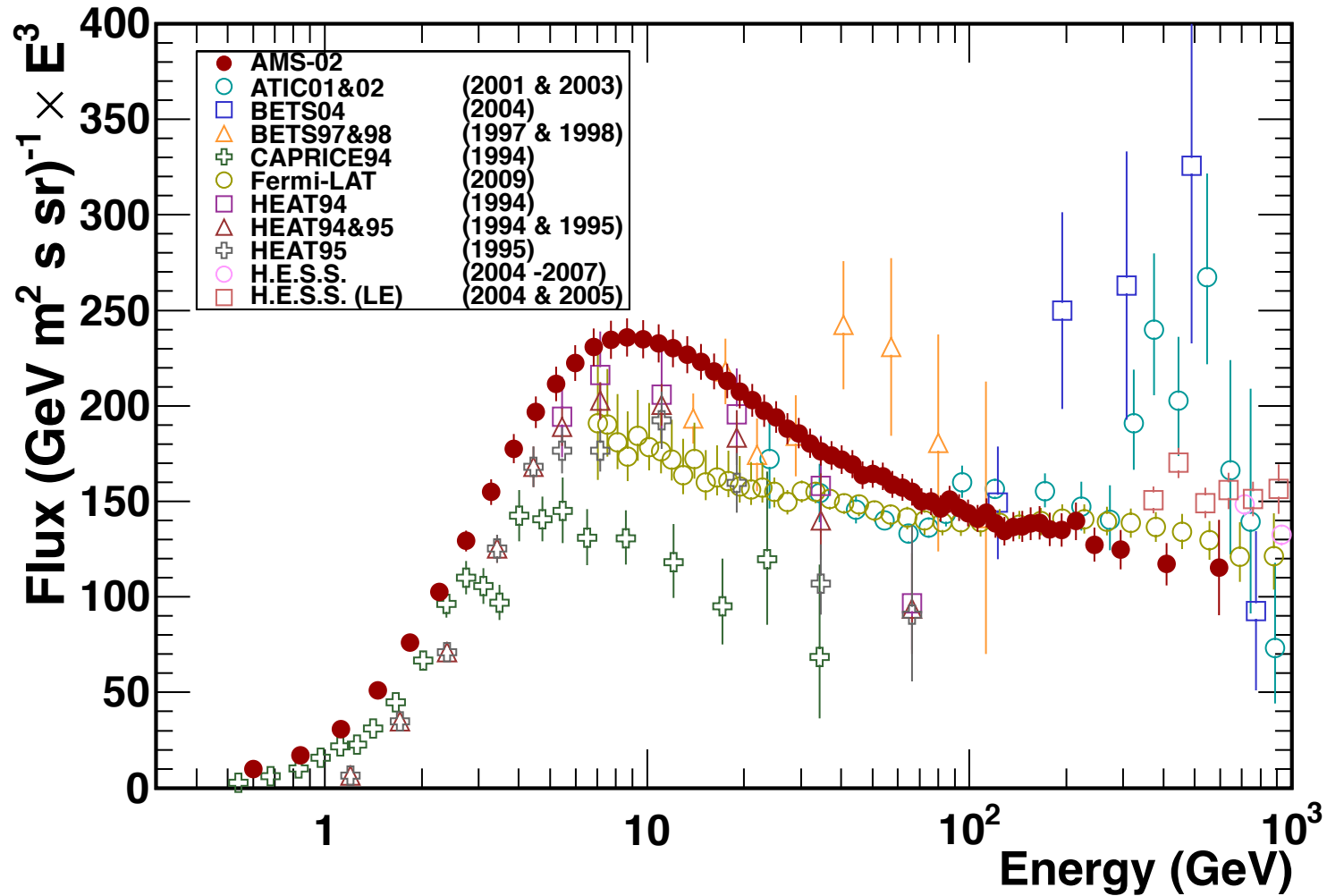
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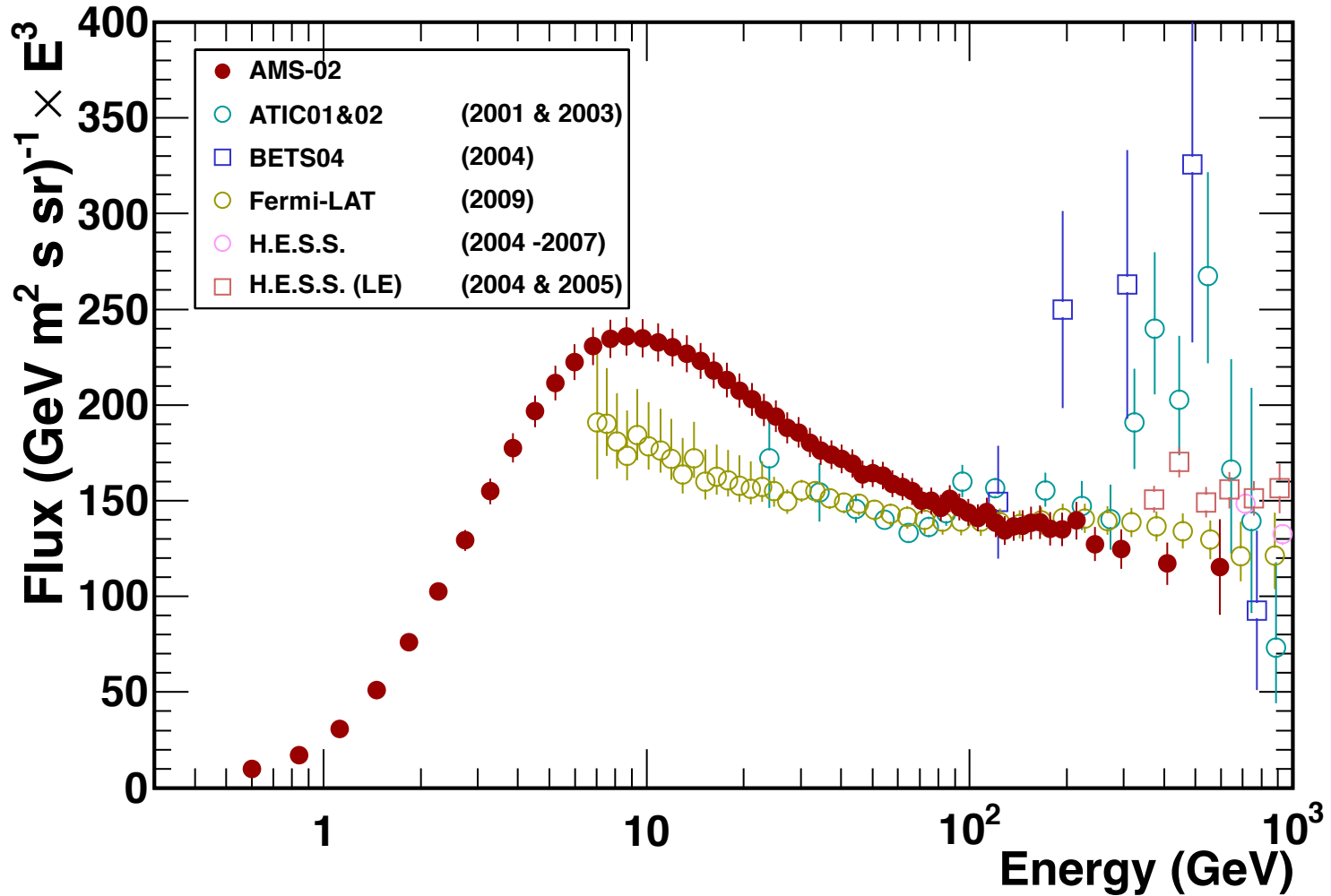
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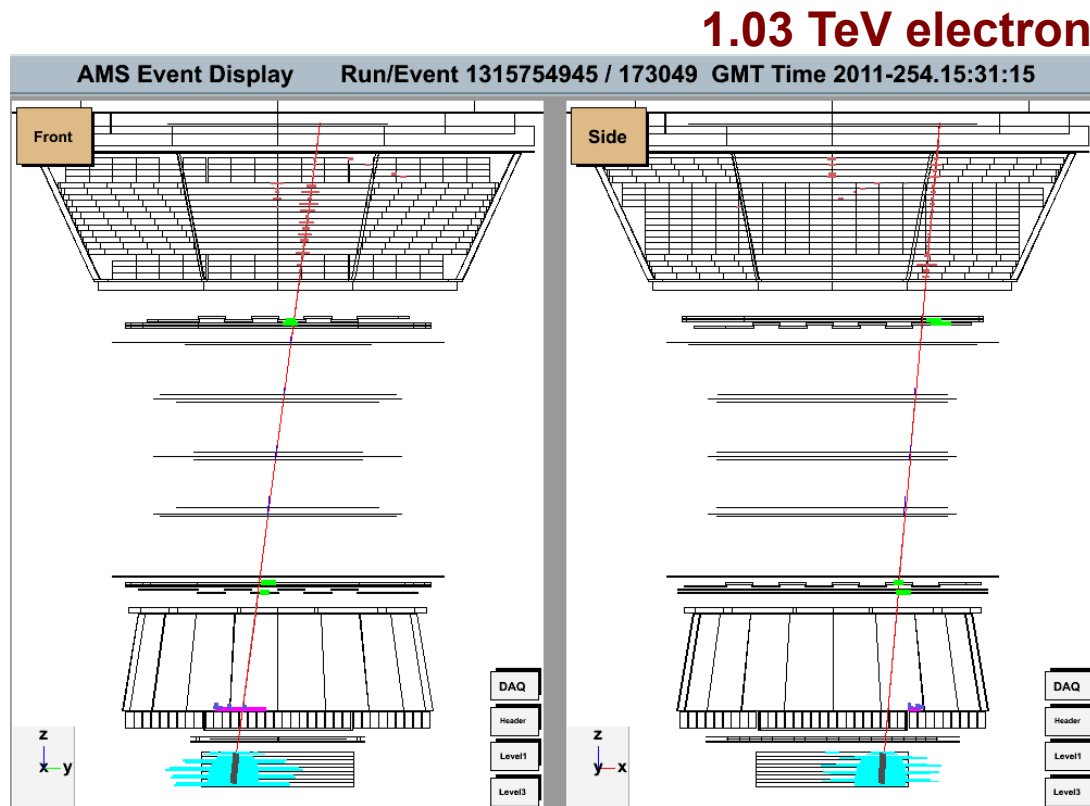


The $(e^- + e^+)$ flux



Conclusions

- 9 million electrons out of ≈ 30 billion triggers have been used to measure the $e^+ + e^-$ spectrum up to 700 GeV.
- This corresponds to $\approx 10\%$ of the expected data sample.





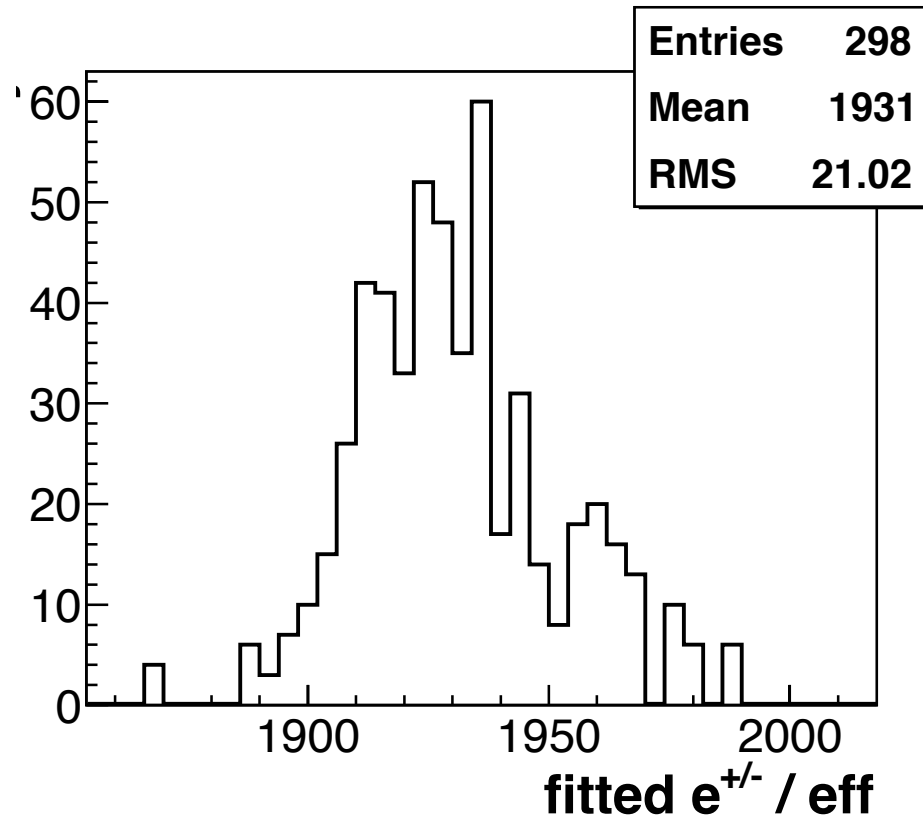
BACKUP

Systematics

- Selection MC/Data comparison $\approx 2-3\%$
- Normalization Track/No-Track analysis $\approx 3\%$
- Energy smearing ($< 2 \text{ GeV}$) $\approx 1\%$
- Stability vs BDT cut efficiency $\approx 1\%$
- TRD-LLE Reference distribution for protons $\approx 1\%$

Systematic error: stability of the signal vs ECAL BDT cut

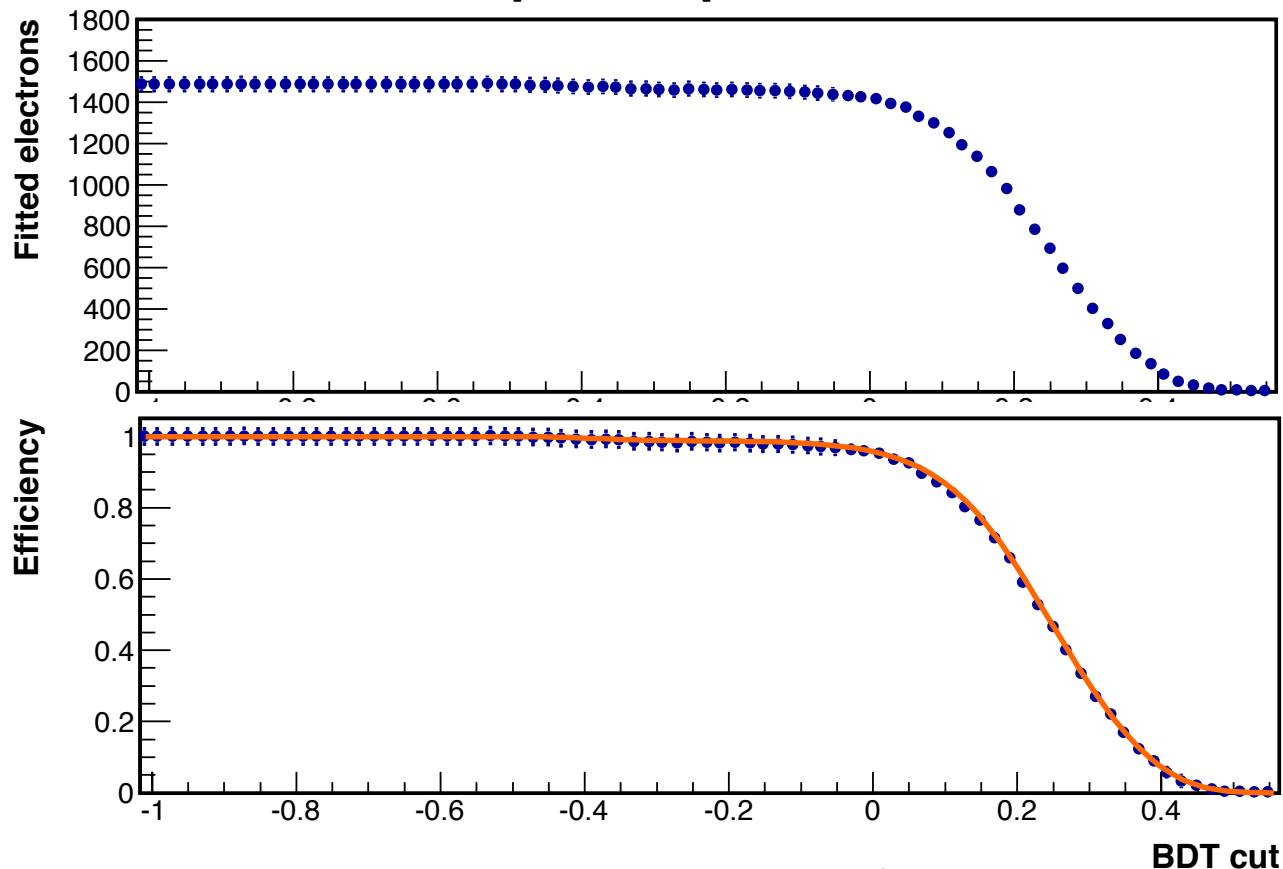
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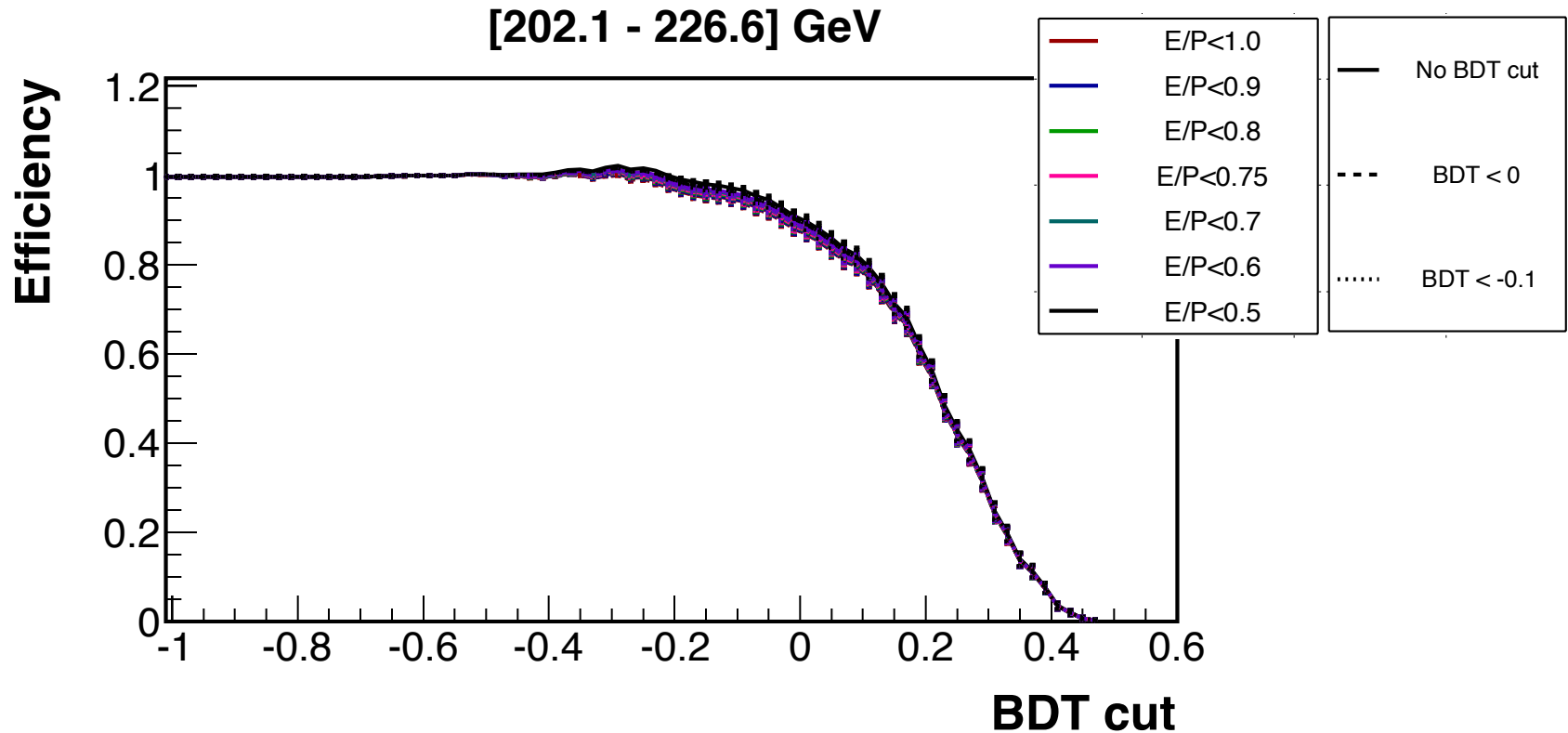
BDT cut Efficiency

An enriched sample in electrons is selected by means of negative sign of the charge, E/P matching

The same fitting procedure as on the full sample is applied in order to estimate the number of electrons as a function of the BDT cut.

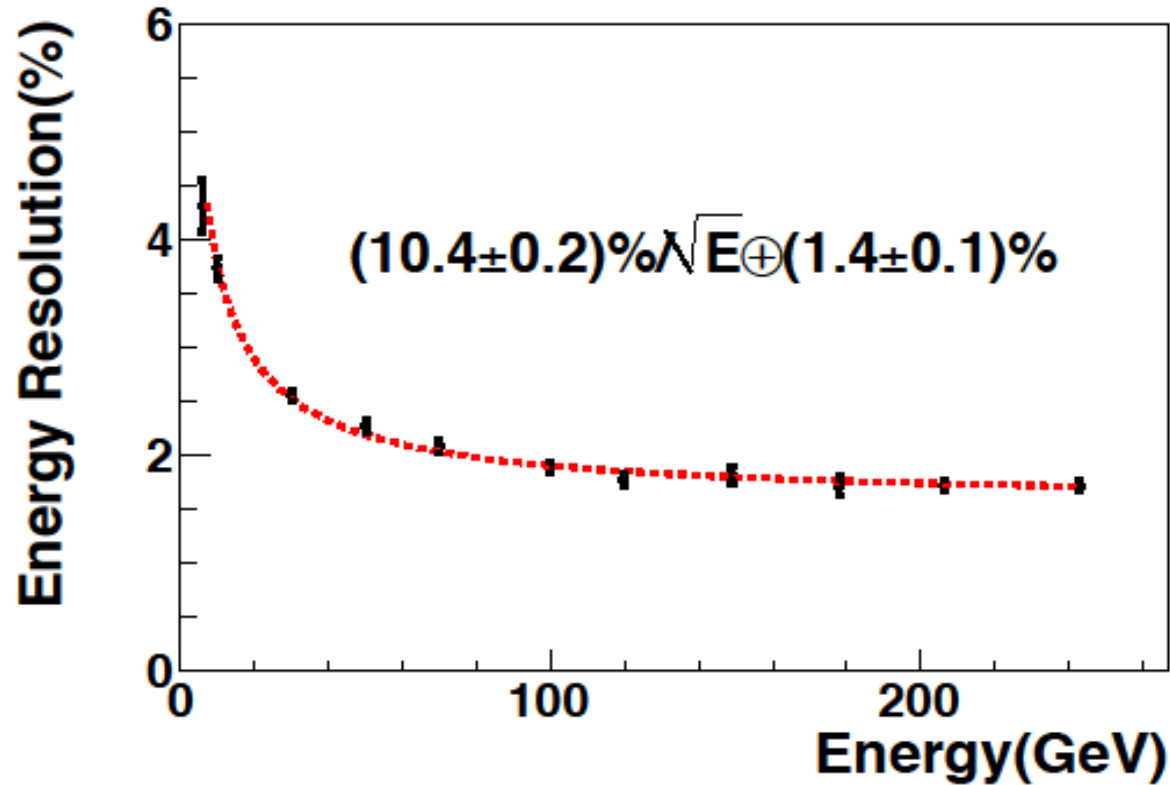


Systematics on the template



Use different 21 different selections varying (E/p , BDT) to define the proton template and see the effect on the measurement.

Systematics: bin-to-bin migration



High energy effects

- ECAL energy scale for a single cell is linear from 2 MeV up to 60 GeV
- Thanks to the ECAL granularity the energy is shared among many cells
- This allows to measure the energy of electrons up to the TeV with minor saturation effects

